



Sheet 1 of 1

Based on Form 100-1 (3/90)  <b>LIST OF REFERENCES CITED BY APPLICANT</b> (Use several sheets if necessary)	<b>ATTY. DOCKET NO.</b> 450100-04774	<b>SERIAL NO.</b> 10/527,137
	<b>APPLICANT</b> Tatsuya DEGUCHI et al.	
	<b>FILING DATE</b> March 8, 2005	<b>GROUP</b> 2612

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/A.H./	AL	2001 311977	11/09/01	Japan			YES
/A.H./	AM	2002 209138	07/26/02	Japan			YES
	AN						
	AO						
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
	AR						
	AS						

<b>EXAMINER</b>  /Amy Hsu/	<b>DATE CONSIDERED</b>  09/17/2007
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450100-04774	SERIAL NO. Filed Concurrently Herewith
	APPLICANT Tatsuya DEGUCHI et al.	
	FILING DATE Filed Concurrently Herewith	GROUP

LIST OF REFERENCES CITED BY APPLICANT  
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
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	AG						
	AH						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/A.H./	AI	JP 2002-92607	03/29/02	Japan			
↓	AJ	JP 2002-238013	08/23/01	Japan			
↓	AK	JP 2001-285641	10/12/01	Japan			
↓	AL	JP 2000-307896	11/02/00	Japan			
↓	AM	JP 11-298792	10/29/99	Japan			
↓	AN	JP 9-93464	04/04/97	Japan			
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
	AQ		Tetsuro KUWAYAMA, "IEC TC100 no Doko, The Institute of Image Electronics Engineers of Japan, 25 January, 2001, Vol. 30, No. 1, pages 30 to 34
	AR		
	AS		

EXAMINER  /Amy Hsu/	DATE CONSIDERED  09/17/2007
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Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450100-04774	INT'L APPL. NO. PCT/JP03/10779
	APPLICANT Tatsuya DEGUCHI et al.	
	INT'L FILING DATE August 26, 2003	GROUP 2612

LIST OF REFERENCES CITED BY APPLICANT  
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/A.H./	AA	2002 0024609	02/28/02	Matsushima			
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	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/A.H./	AL	JP 2002 238013	08/23/02	Japan			X
/A.H./	AM	JP 2000 307896	11/02/00	Japan			X
/A.H./	AN	JP 11 298792	10/29/99	Japan			X
/A.H./	AO	JP 9 93464	04/04/97	Japan			X
/A.H./	AP	JP 2001 285641	10/12/01	Japan			X

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
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EXAMINER  /Amy Hsu/	DATE CONSIDERED  09/17/2007
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